96D 80742

T-33-13

# MOTOROLA SEMICONDUCTOR **TECHNICAL DATA**

# BUS48P

### **SWITCHMODE II** SERIES **NPN SILICON POWER TRANSISTORS**

The BUS 48P/BUS 48AP transistors are designed for highvoltage, high-speed, power switching in inductive circuits where fall time is critical. They are particularly suited for line-operated switchmode applications such as:

- Switching Regulators
- Inverters
- Solenoid and Relay Drivers
- Motor Controls
- Deflection Circuits

Fast Turn-Off Times

60 ns Inductive Fall Time - 25°C (Typ) 120 ns Inductive Crossover Time - 25°C (Typ)

Operating Temperature Range -65 to +175°C 100°C Performance Specified for: Reverse-Biased SOA with Inductive Loads Switching Times with Inductive Loads

Saturation Voltages Leakage Currents (125°C)



Rating	Symbol	BUS 48P	BUS 48AP	Unit
Collector-Emitter Voltage	V <sub>CEO(sus)</sub>	400	450	Vdc
Collector-Emitter Voltage	VCEV	850	1000	Vdc
Emitter Base Voltage	V <sub>EB</sub>		7	Vdc
Collector Current — Continuous — Peak(1) — Overload	I <sub>CM</sub>	15 30 60		Adc
Base Current - Continuous - Peak(1)	I <sub>B</sub>	5 20		Adc
Total Power Dissipation - T <sub>C</sub> = 25°C - T <sub>C</sub> = 100°C  Derate above 25°C	PD	150 75 1.0		Watts W/°C
Operating and Storage Junction Temperature Range	Tj, T <sub>stg</sub>	-65 to +′175		ပ္

### THERMAL CHARACTERISTICS

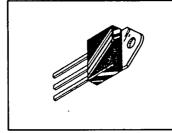
Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	Revc	1.0	°C/W
Maximum Lead Temperature for Soldering Purposes: 1/8" from Case for 5 Seconds	ΤL	275	°C

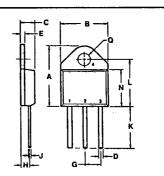
(1) Pulse Test: Pulse Width = 5 ms, Duty Cycle ≤ 10%.

# 15 AMPERES

### **NPN SILICON POWER TRANSISTORS**

400 and 450 VOLTS (BVCEO) 850 - 1000 VOLTS (BVCES) 150 WATTS





### STYLE 1:

- 1. BASE
  2. COLLECTOR
  3. EMITTER
  4. COLLECTOR

	MILLIM	ETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
A	20.32	21.08	0.800	0.830
В	15.49	15.90	0.610	0.626
Ç.,	4.19	5.08	0.165	0.200
D	1.02	1.65	0.040	0.065
E	1.35	1.65	0.053	0.065
G	5.21	5.72	0.205	0.225
H	2.41	3.20	0.095	0.126
J	0.38	0.64	0.015	0.025
K	12.70	15.49	0.500	0.610
L	15.88	16.51	0.625	0.650
N	12.19	12.70	0.480	0.500
Π	3.04	A 19	0.155	N 165

CASE 340-01 TO-218AC



# 6367254 MOTOROLA SC\_(XSTRS/R F)

**BUS48P, BUS48AP** 

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### ELECTRICAL CHARACTERISTICS (T<sub>C</sub> = 25°C unless otherwise noted)

Characteristic		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS (1)	<del>-</del>					
Collector-Emitter Sustaining Voltage (Table 1) (IC = 200 mA, IB = 0) L = 25 mH	BUS48P BUS48AP	V <sub>CEO(sus)</sub>	400 450	-	-	Vdc
Collector Cutoff Current (VCEV = Rated Value, VBE(off) = 1.5 Vdc) (VCEV = Rated Value, VBE(off) = 1.5 Vdc, TC	= 125°C)	ICEV	<u> </u>		0.2 2.0	mAdc
Collector Cutoff Current (VCE = Rated VCEV, RBE = 10 Ω)	T <sub>C</sub> = 25°C T <sub>C</sub> = 125°C	ICER		-	0.5 3.0	mAdc
Emitter Cutoff Current (VEB = 5 Vdc, IC = 0)		<sup>1</sup> EBO	1	_	0.1	mAdc
Emitter-base breakdown Voltage (IE = 50 mA - IC = 0)		BVEBO	7.0			Vdc
SECOND BREAKDOWN						
Second Breakdown Collector Current with Base F	IS/b	See Figure 12				
Clamped Inductive SOA with Base Reverse Biased	RBSOA	See Figure 13			J	
ON CHARACTERISTICS (1)						
DC Current Gain (IC = 10 Adc, VCE = 5 Vdc) (IC = 8 Adc, VCE = 5 V)	BUS48 BUS48A	pEE	8	_	_	
Collector-Emitter Saturation Voltage (IC = 10 Adc, IB = 2 Adc) (IC = 15 Adc, IB = 3 Adc) (IC = 10 Adc, IB = 3 Adc) (IC = 10 Adc, IB = 2 Adc, TC = 100°C) (IC = 8 Adc, IB = 1.6 Adc) (IC = 12 Adc, IB = 2.4 Adc) (IC = 8 Adc, IB = 1.6 Adc, TC = 100°C)	BUS48P	VCE(sat)	1 1 1 1 1	11111	1.5 5.0 2.0 1.5 5.0 2.0	Vdc
Base-Emitter Saturation Voltage (I <sub>C</sub> = 10 Adc, I <sub>B</sub> = 2 Adc) (I <sub>C</sub> = 10 Adc, I <sub>B</sub> = 2 Adc, T <sub>C</sub> = 100°C) (I <sub>C</sub> = 8 Adc, I <sub>B</sub> = 1.6 Adc)	BUS48P BUS48AP	VBE(sat)	- - -	- - -	1.6 1.6 1.6	Vdc
(IC = 8 Adc, IB = 1.6 Adc, TC = 100°C)  DYNAMIC CHARACTERISTICS		<u> </u>		<u> </u>	1.0	
Output Capacitance		Cob				pF

- 1						i i
	Output Capacitance	Cob	1		l	pF
		l cop		ł	!	
1	(V <sub>CB</sub> = 10 Vdc, I <sub>E</sub> = 0, f <sub>test</sub> = 100 Khz)	1	_	_	350	
- 1	TOB TO THE THE TEST	1			l	

### SWITCHING CHARACTERISTICS

### Resistive Load (Table 1)

Delay Time		td	T -	0.1	0.2	μs
Rise Time	(V <sub>CC</sub> = 250 Vdc, I <sub>C</sub> = 10 A,	t <sub>r</sub>	_	0.4	0.7	
Storage Time	$t_{B1} = 2.0 \text{ A, } t_p = 30 \mu\text{s,}$ Duty Cycle 2 , $V_{BE(off)} = 5 \text{V}$	ts	-	1.3	2.0	
Fall Time	2-10-17	tf		0.2	0.4	

### Inductive Load, Clamped (Table 1)

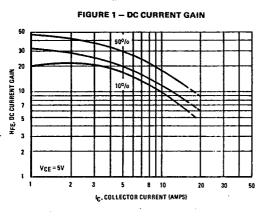
Storage Time		(T <sub>C</sub> = 25°C)	t <sub>sv</sub>	T	1.3	-	μs
Fall Time	$(I_{C(pk)} = 10 A,$	[	tfi		0.06		
Storage Time	I <sub>B1</sub> = 2.0 A, V <sub>BE(off)</sub> = 5 V, V <sub>CE(c1)</sub> = 250 V)		tsv	_	1.5	2.5	
Crossover Time		(T <sub>C</sub> = 100°C)	t <sub>c</sub>	_	0.3	0.6	
Fall Time			tfi	T -	0.17	0.35	

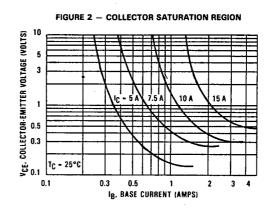
(1) Pulse Test: PW = 300 µs, Duty Cycle ≤ 2%.

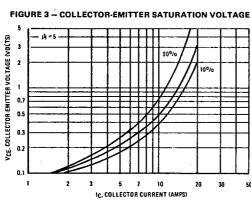


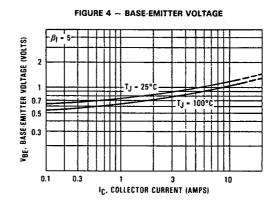
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### DC CHARACTERISTICS

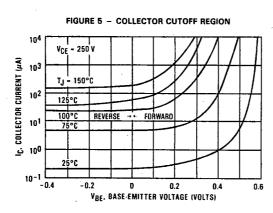


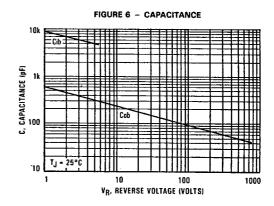










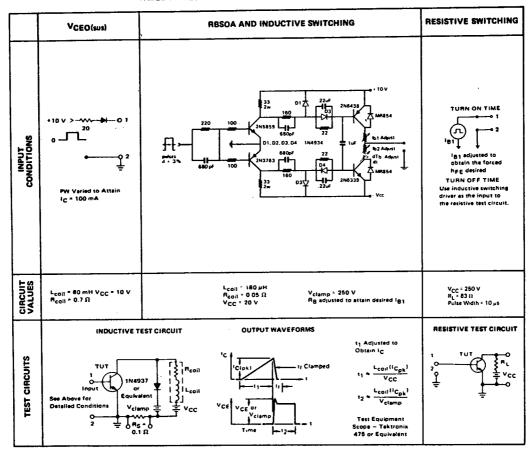


6367254 MOTOROLA SC (XSTRS/R F) BUS48P, BUS48AP

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TABLE 1 - TEST CONDITIONS FOR DYNAMIC PERFORMANCE







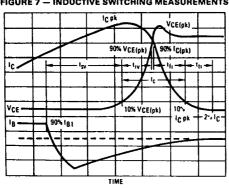
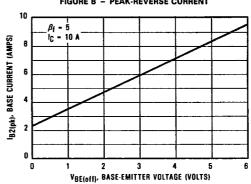


FIGURE 8 - PEAK-REVERSE CURRENT



### 6367254 MOTOROLA SC (XSTRS/R F)

**BUS48P, BUS48AP** 

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### **SWITCHING TIMES NOTE**

In resistive switching circuits, rise, fall, and storage times have been defined and apply to both current and voltage waveforms since they are in phase. However, for inductive loads which are common to SWITCHMODE power supplies and hammer drivers, current and voltage waveforms are not in phase. Therefore, separate measurements must be made on each waveform to determine the total switching time. For this reason, the following new terms have been defined.

tsv = Voltage Storage Time, 90% IB1 to 10% Vclamp

trv = Voltage Rise Time, 10-90% Vclamp

tfi = Current Fall Time, 90-10% IC

tti = Current Tail, 10-2% IC

tc = Crossover Time, 10% V<sub>clamp</sub> to 10% IC

An enlarged portion of the inductive switching waveforms

is shown in Figure 7 to aid in the visual identity of these terms.

For the designer, there is minimal switching loss during storage time and the predominant switching power losses occur during the crossover interval and can be obtained using the standard equation from AN-222:

PSWT = 1/2 VCCIC(tc)f In general,  $t_{rv} + t_{fi} \cong t_c$ . However, at lower test currents

this relationship may not be valid. As is common with most switching transistors, resistive switching is specified at 25°C and has become a benchmark for designers. However, for designers of high frequency converter circuits, the user oriented specifications which make this a "SWITCHMODE" transistor are the inductive switching speeds ( $t_C$  and  $t_{SV}$ ) which are guaranteed at 100°C.

### INDUCTIVE SWITCHING

FIGURE 9 - STORAGE TIME, Tay

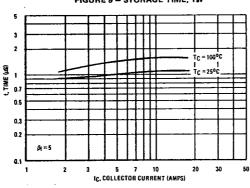


FIGURE 11a- TURN-OFF TIMES vs FORCED GAIN

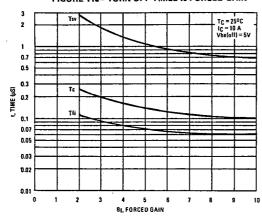


FIGURE 10 - CROSSOVER AND FALL TIMES

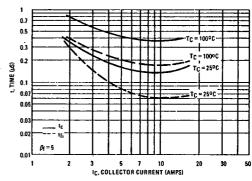
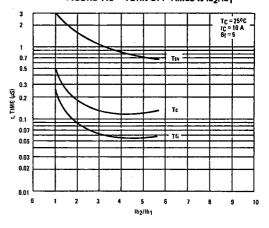


FIGURE 11b - TURN-OFF TIMES vs Ib2/Ib1





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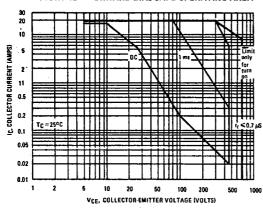
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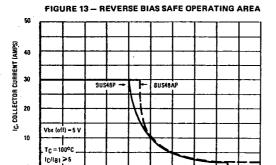
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The Safe Operating Area figures shown in Figures 12 and 13 are specified for these devices under the test conditions shown.

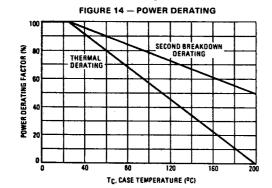
FIGURE 12 - FORWARD BIAS SAFE OPERATING AREA





400

VCE, COLLECTOR-EMITTER VOLTAGE (VOLTS)



### SAFE OPERATING AREA INFORMATION

### **FORWARD BIAS**

There are two limitations on the power handling ability of a transistor: average junction temperature and second breakdown. Safe operating area curves indicate IC-VCE limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 12 is based on  $T_C = 25^{o}C$ ;  $T_{J(pk)}$  is variable depending on power level. Second breakdown pulse limits are valid for duty cycles to 10% but must be derated when  $T_C \ge 25^{o}C$ . Second breakdown limitations do not derate the same as thermal limitations. Allowable current at the voltages shown on Figure 12 may be found at any case temperature by using the appropriate curve on Figure 14.

 $T_{J(pk)}$  may be calculated from the data in Figure 11. At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown.

### REVERSE BIAS

For inductive loads, high voltage and high current must be sustained simultaneously during turn-off, in most cases, with the base to emitter junction reverse biased. Under these conditions the collector voltage must be held to a safe level at or below a specific value of collector current. This can be accomplished by several means such as active clamping, RC snubbing, load line shaping, etc. The safe level for these devices is specified as Reverse Bias Safe Operating Area and represents the voltage-current conditions during reverse biased turn-off. This rating is verified under clamped conditions so that the device is never subjected to an avalanche mode. Figure 13 gives RBSOA characteristics.

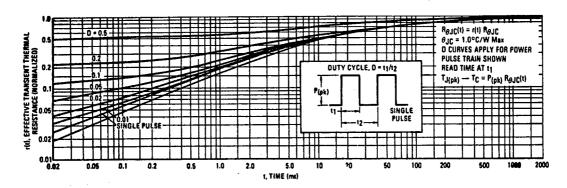


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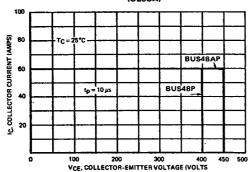
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FIGURE 15 - THERMAL RESPONSE

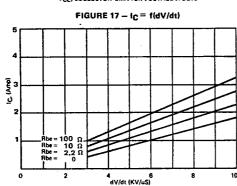


### **OVERLOAD CHARACTERISTICS**

FIGURE 16 - RATED OVERLOAD SAFE OPERATING AREA (OLSOA)







### **OLSOA**

OLSOA applies when maximum collector current is limited and known. A good example is a circuit where an inductor is inserted between the transistor and the bus, which limits the rate of rise of collector current to a known value. If the transistor is then turned off within a specified amount of time, the magnitude of collector current is also known.

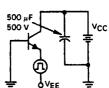
Maximum allowable collector-emitter voltage versus collector current is plotted for several pulse widths. (Pulse width is defined as the time lag between the fault condition and the removal of base drive.) Storage time of the transistor has been factored into the curve. Therefore, with bus voltage and maximum collector current known, Figure 16 defines the maximum time which can be allowed for fault detection and shutdown of base drive.

OLSOA is measured in a common-base circuit (Figure 18) which allows precise definition of collectoremitter voltage and collector current. This is the same circuit that is used to measure forward-bias safe operating area.

### FIGURE 18 - OVERLOAD SOA TEST CIRCUIT

### Notes:

- ◆ VCE = VCC + VBE
- Adjust pulsed current source for desired IC, tp



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